Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/050,334	AGARWAL ET AL.
Examiner	Art Unit
Yennhu B. Huynh	2813

SEARCHED						
Class	Subclass	Date	Examiner			
257	296	3205	75			
	301->					
	309					
	751					
	310 311 5321					
438	2391	s u o				
	396 ->					
-	399					
	386					
	2537	,				
·	257	,	NS			
	243		1/			
1065, 627, 653, 925 INTERFERENCE SEARCHED						
INTERFERENCE SEARCHED						

Examiner

Date

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Si west East USPAT E PU JPO Securit IDMISI (attack)	3/3/cs	YP
(attack)		
A_000 A		
•		

Class

Subclass